

# GPI65030DFN

#### N-channel 650V 30A GaN Power HEMT in 8X8 DFN package

#### Datasheet version: 2.1

#### **Features**

BV <sub>dss</sub>	R <sub>dson</sub>	l <sub>ds</sub>	Qg
650 V	55 mΩ	30 A	5.8 nC

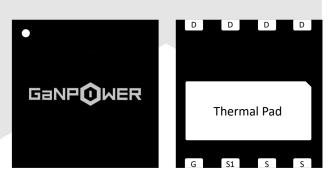
- Ultra-low RDS(on)
- High dv/dt capability
- Extremely low input capacitance
- Zero Qrr
- Outstanding switching performance
- Low Profile

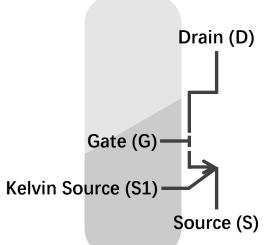
#### **Applications**

- Switching Power Applications
- Adapters, Quick Chargers

### **Description**

These devices are N-channel 650 V Power GaN HEMTs based on proprietary E-mode GaN on silicon technology. The resulting product has extremely low on state resistance, very low input capacitance and zero reverse recovery charge making it especially suitable for applications which require superior power density, ultra-high switching frequency and outstanding efficiency.







### **Device Characteristics**

Static Parameters			Test data				
	Parameters		Conditions	Min	Typical	Max	Unit
1	V <sub>gs(TH)</sub>	Gate threshold voltage	V <sub>ds</sub> =V <sub>gs</sub> Id=3.5mA	1.0	1.2	1.4	V
2	BV <sub>dss</sub>	Drain-Source breakdown voltage	V <sub>gs</sub> =0V I <sub>d</sub> =25uA		650		V
3	l <sub>dss</sub>	Zero gate voltage drain current, T <sub>C</sub> = 25C°	V <sub>gs</sub> =0V V <sub>ds</sub> =650V		1.5	40	uA
4	l <sub>gss</sub>	Gate-Source Leakage	V <sub>gs</sub> = 6V V <sub>ds</sub> =0V		100	150	uA
5	R <sub>dson</sub>	Static drain-source on resistance, $T_c = 25C^{\circ}$	V <sub>gs</sub> =6V I <sub>d</sub> =2.5A		55	65	mΩ
6	$V_{sd}$	Reverse conduction voltage	I <sub>sd</sub> =1A V <sub>gs</sub> =0V	1.65	1.85	2.0	V
7	R <sub>g</sub>	Gate resistance	F=25MHz		1.2		Ω
Dynamic Parameters			Test data				
Dyr	ianne i arannee	ers			Test d	ata	
Dyr	Parameters		Conditions	Min	Test d	ata Max	Unit
	Parameters C <sub>iss</sub>	Input capacitance	V <sub>gs</sub> =0V	Min	Typical 241		pf
Dyr 1	Parameters C <sub>iss</sub> C <sub>oss</sub>	Input capacitance Output capacitance	V <sub>gs</sub> =0V V <sub>ds</sub> =400V	Min	<b>Typical</b> 241 61		pf pf
	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>gs</sub> =0V V <sub>ds</sub> =400V f=1MHz	Min	<b>Typical</b> 241 61 8.4		pf pf pf
	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Q <sub>g</sub>	Input capacitance Output capacitance Reverse transfer capacitance Gate charge	V <sub>gs</sub> =0V V <sub>ds</sub> =400V	Min	<b>Typical</b> 241 61		pf pf
1	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Q <sub>g</sub> Q <sub>gs</sub>	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge	V <sub>gs</sub> =0V V <sub>ds</sub> =400V f=1MHz V <sub>ds</sub> =400V	Min	Typical           241           61           8.4           5.8		pf pf pf nC
1	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Q <sub>g</sub>	Input capacitance Output capacitance Reverse transfer capacitance Gate charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A$	Min	Typical           241           61           8.4           5.8           1.2		pf pf pf nC nC
1 3 2	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A$	Min	Typical           241           61           8.4           5.8           1.2           1.5	Max	pf pf pf nC nC nC
1 3 2	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub> Q <sub>rr</sub>	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A$	Min	Typical           241           61           8.4           5.8           1.2           1.5           0	Max	pf pf pf nC nC nC
1 3 2	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub> Q <sub>rr</sub> tching Perform	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V$ $V_{ds}=400V$ $f=1MHz$ $V_{ds}=400V$ $I_{d}=7.5A$ $V_{gs}=6V$ Conditions		Typical           241           61           8.4           5.8           1.2           1.5           0           Test data	Max	pf pf nC nC nC nC
1 3 2 Swi	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub> Q <sub>rr</sub> tching Perform Parameters	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	V <sub>gs</sub> =0V V <sub>ds</sub> =400V f=1MHz V <sub>ds</sub> =400V I <sub>d</sub> =7.5A V <sub>gs</sub> =6V		Typical           241           61           8.4           5.8           1.2           1.5           0           Test data	Max	pf pf nC nC nC nC
1 3 2 Swi	Parameters C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub> Q <sub>rr</sub> tching Perform Parameters t <sub>d(on)</sub>	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A \\ V_{gs}=6V \\ \hline \\ $		Typical           241           61           8.4           5.8           1.2           1.5           0           Test day           6	Max	pf pf nC nC nC nC nC



## Absolute Max. Ratings

	Symbols	Parameters	Value	Unit
1	V <sub>DS-max</sub>	Breakdown voltage transient @ T <sub>case</sub> =25°C	800	V
2	$V_{GS-max}$	Gate to source max. transient voltage @ T <sub>case</sub> =25°C	-12 to +7.5	V
3	I <sub>ds-max</sub>	Drain to source DC current @ T <sub>case</sub> =25°C	30	А
4	I <sub>ds-max</sub>	Drain to source DC current @ T <sub>case</sub> =100°C	24	А
5	dv/dt- <sub>max</sub>	Drain to source voltage slew rate	200	V/nS
6	T <sub>J-max</sub>	Max junction temperature	150	°C
7	T <sub>S-storage</sub>	Storage temperature	-55 to 150	°C

### Thermal and Soldering Characteristics (Typical)

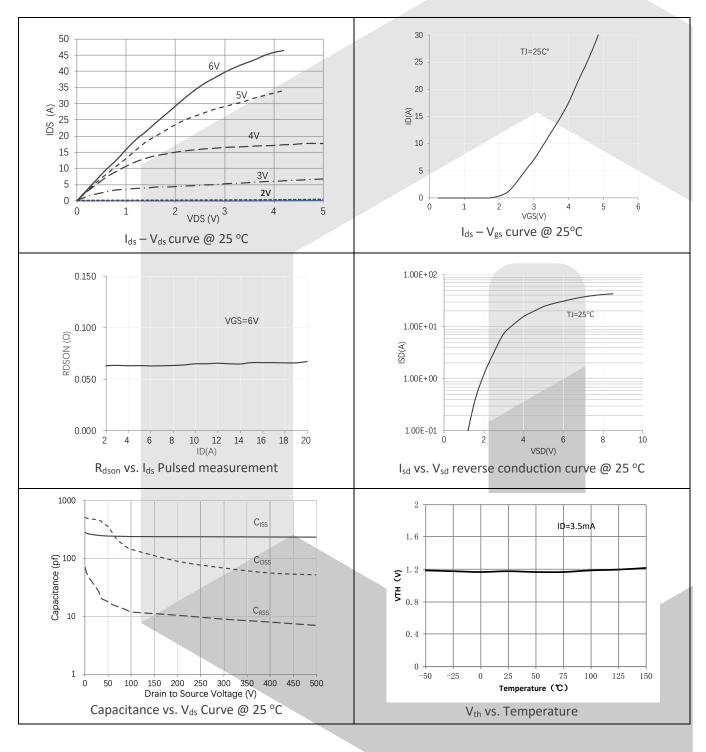
	Symbols	Parameters	Value	Unit
1	R <sub>thJC</sub>	Thermal resistance (junction to case)	0.95	°C /W
2	T <sub>solder</sub>	Reflow soldering temperature	250	°C

#### **Ordering**

Order Code	Package Type	Packaging Method	Qty	
GPI65030DFO	DFN surface mount, bottom cooled, 6X8 mm	Tape and Reel	3500	

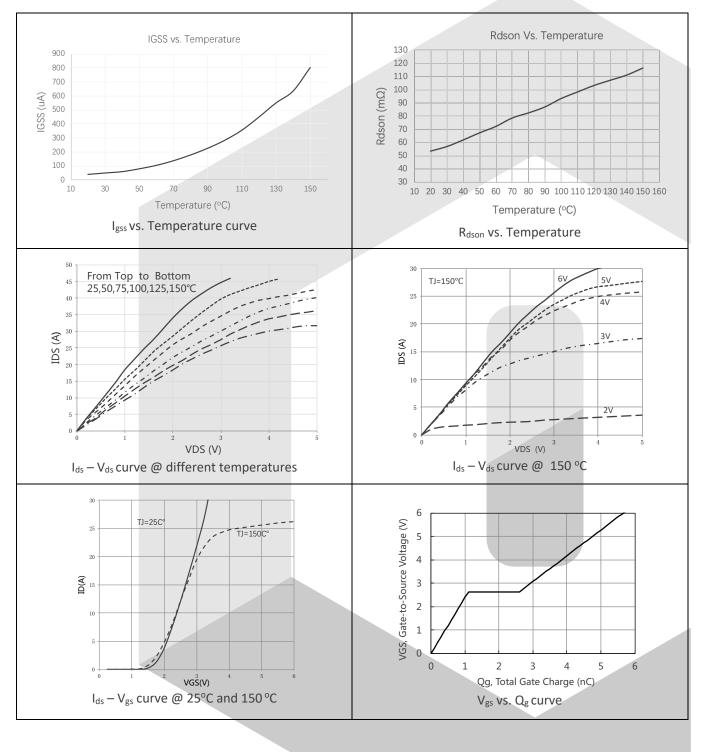


### **Electrical Performance**



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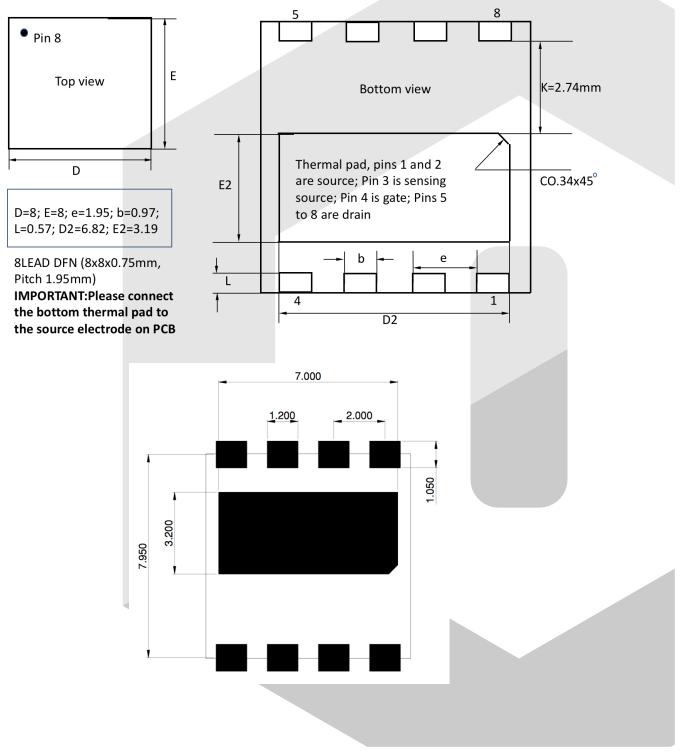




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### Package Information





#### **GaN HEMT Frequently Asked Questions**

1	Q: Can we do pin to pin switch for silicon MOSFET or IGBT?
	A: The short answer is no. GaN HEMT power devices are far superior than the best silicon
	devices such as super junction MOSFETs. However, due to different requirements of gate
	driving voltage and extremely high dv/dt slew rate, special drivers and optimized PCB layouts
	are recommended to minimize the impact from circuit parasitics. Some packaging forms such
	as GaNPower's DFN packaged devices offer both sense and force for the source terminal. Also,
	for traditional TO220 packages, please be advised that the pins are arranged as Gate – Source
	-Drain, and the thermal pad is connected to the source instead of drain.
2	Q: Are GaN power devices reliable?
	A: GaN power HEMTs have been tested by GaNPower and many other vendors, users and
	testing facilities to be as reliable (if not better than) silicon counterparts.
3	Q: How do GaN power devices compare with SiC?
	A: Currently GaN power HEMT devices are most suitable for low to medium voltage ( $\leq$ 1200V)
	and power (<20KW) applications. GaN is the ideal choice for high frequency applications. SiC
	devices are better choice for high voltage and high-power applications (>20KW).
4	Q: Do we need to parallel an FRD for applications such as inverters?
	A: GaN devices are different from silicon MOSFET or IGBT in that they have no inherent PN
	junction diodes that cause reverse recovery issue. User do not need to parallel an FRD for the
	purpose of suppressing the body diode reverse recovery effect, since GaN HEMT can operate
	in both first and third quadrants. However, care should be taken for the dead time power loss
	since the Vsd voltage of GaN HEMT is usually close to 2V. This is especially true when a negative
	gate voltage is applied.
6	Q: Can we parallel GaN HEMT devices?
	A: Yes, GaN HEMT is ideal for paralleling, due to positive temperature coefficient of Rdson
_	and slightly positive temperature coefficient of threshold voltage.
5	Q: Where can we find drivers for GaNPower HEMT devices?
	A: While some of the GaNPower's HEMTs are either monolithically integrated with gate
	driver or co-packaged with a silicon driver, drivers can be easily found from vendors such as
	TI and Silicon Lab for either single sided or half-bridge configurations: ✓ TI: LM5114: Single 7.6A Peak Current Low-Side Gate Driver
	<ul> <li>✓ <u>TI: UCC27611</u>: 5V, 4A/6A Low Side GaN Driver</li> <li>✓ Maxim: MAX5048C: 7A Sink/3A Source Current, 8ns, SOT23, MOSFET Drive</li> </ul>
	<ul> <li>Fairchild: FAN3122: Single 9-A High-Speed, Low-Side Gate Driver</li> <li>Silicon Lab: Si827X: 4 Amp ISO driver with High Transient (dv/dt) Immunity</li> </ul>
	Sincon Lab. Sio27A. 4 Amp iso unver with high transient (uv/ut) inimulity